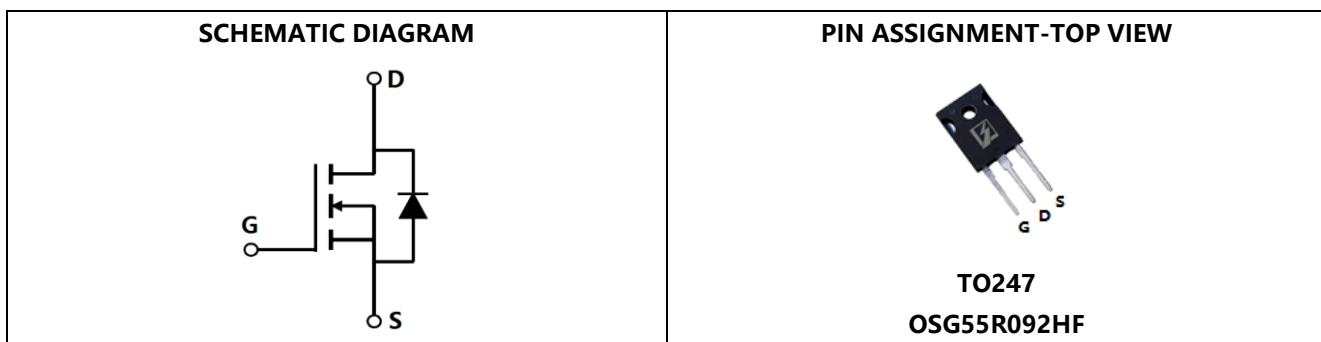


■ General Description

OSG55R092HF use advanced GreenMOS™ technology to provide low $R_{DS(ON)}$, low gate charge, fast switching and excellent avalanche characteristics. This device is suitable for telecom and super charger applications.

◆ V_{DS} , min@ T_{jmax}	600 V
◆ I_D , pulse	120 A
◆ $R_{DS(ON)}$, max @ $V_{GS}=10$ V	92 mΩ
◆ Q_g	38.6 nC

■ Schematic and Package Information



■ Absolute Maximum Ratings at $T_j=25^\circ\text{C}$ unless otherwise noted

PARAMETER	SYMBOL	VALUE	UNIT
Drain source voltage	V_{DS}	550	V
Gate source voltage	V_{GS}	± 30	V
Continuous drain current ¹⁾ , $T_C=25^\circ\text{C}$	I_D	40	A
Continuous drain current ¹⁾ , $T_C=100^\circ\text{C}$		25	
Pulsed drain current ²⁾ , $T_C=25^\circ\text{C}$	I_D , pulse	120	A
Power dissipation ³⁾ , $T_C=25^\circ\text{C}$	P_D	101	W
Single pulsed avalanche energy ⁵⁾	E_{AS}	770	mJ
MOSFET dv/dt ruggedness, $V_{DS}=0...440$ V	dv/dt	50	V/ns
Reverse diode dv/dt, $V_{DS}=0...440$ V, $I_{SD} \leq I_D$	dv/dt	15	V/ns
Operation and storage temperature	T_{stg} , T_j	-55 to 150	°C

■ Thermal Characteristics

PARAMETER	SYMBOL	VALUE	UNIT
Thermal resistance, junction-case	$R_{\theta JC}$	0.81	°C/W
Thermal resistance, junction-ambient ⁴⁾	$R_{\theta JA}$	62	°C/W

■ Electrical Characteristics at $T_j=25$ °C unless otherwise specified

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	TEST CONDITION
Drain-source breakdown voltage	BV_{DSS}	550			V	$V_{GS}=0$ V, $I_D=1$ mA
		600	670			$V_{GS}=0$ V, $I_D=1$ mA, $T_j=150$ °C
Gate threshold voltage	$V_{GS(th)}$	2.9		3.9	V	$V_{DS}=V_{GS}$, $I_D=1$ mA
Drain-source on-state resistance	$R_{DS(ON)}$		0.078	0.092	Ω	$V_{GS}=10$ V, $I_D=20$ A
			0.183			$V_{GS}=10$ V, $I_D=20$ A, $T_j=150$ °C
Gate-source leakage current	I_{GSS}			100	nA	$V_{GS}=30$ V
				-100		$V_{GS}=-30$ V
Drain-source leakage current	I_{DSS}			1	μA	$V_{DS}=550$ V, $V_{GS}=0$ V

■ Dynamic Characteristics

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	TEST CONDITION
Input capacitance	C_{iss}		2425.5		pF	$V_{GS}=0$ V, $V_{DS}=50$ V, $f=100$ kHz
Output capacitance	C_{oss}		244.3		pF	
Reverse transfer capacitance	C_{rss}		10.3		pF	
Turn-on delay time	$t_{d(on)}$		53.7		ns	$V_{GS}=10$ V, $V_{DS}=400$ V, $R_G=2$ Ω, $I_D=20$ A
Rise time	t_r		79.3		ns	
Turn-off delay time	$t_{d(off)}$		122.9		ns	
Fall time	t_f		59.1		ns	

■ Gate Charge Characteristics

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	TEST CONDITION
Total gate charge	Q_g		38.6		nC	$I_D=20\text{ A}$, $V_{DS}=400\text{ V}$, $V_{GS}=10\text{ V}$
Gate-source charge	Q_{gs}		9.0		nC	
Gate-drain charge	Q_{gd}		15.2		nC	
Gate plateau voltage	$V_{plateau}$		5.9		V	

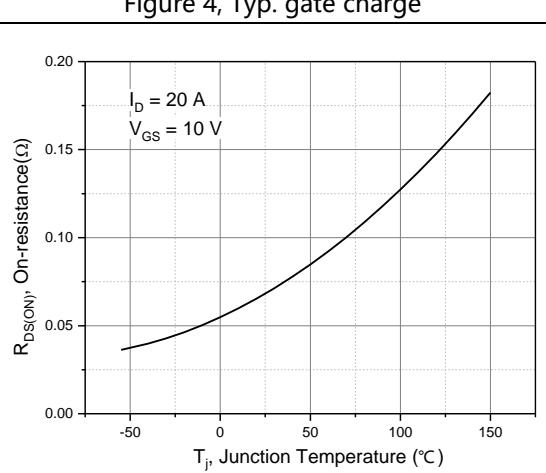
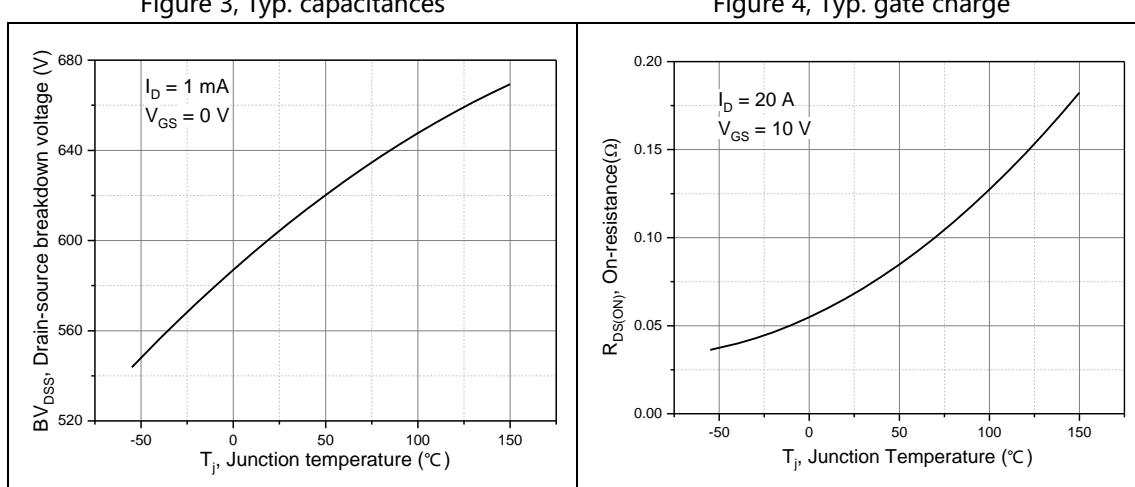
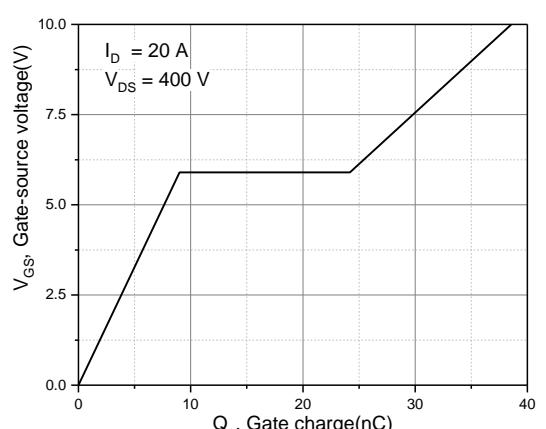
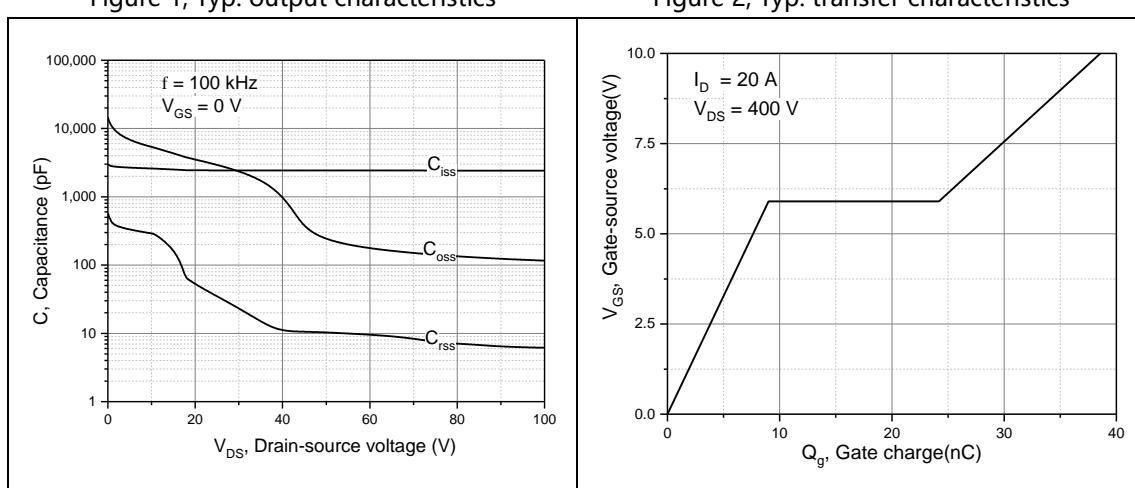
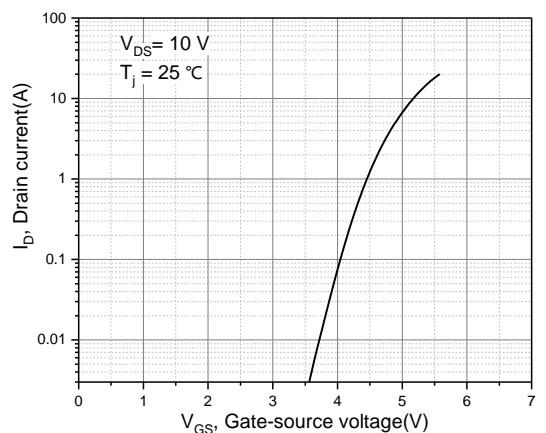
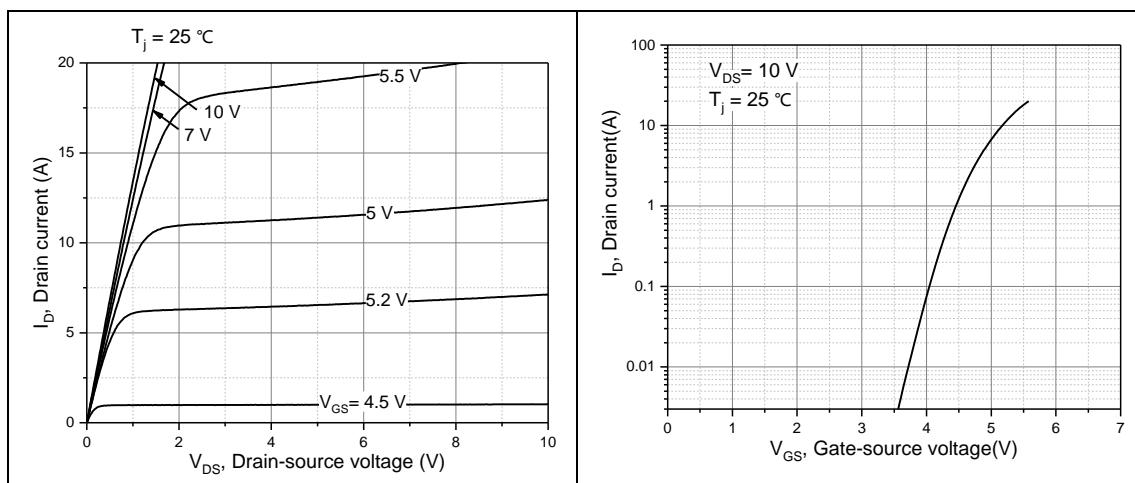
■ Body Diode Characteristics

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	TEST CONDITION
Diode forward current	I_S			40	A	$V_{GS} < V_{th}$
Pulsed source current	I_{SP}			120		
Diode forward voltage	V_{SD}			1.4	V	$I_S=40\text{ A}, V_{GS}=0\text{ V}$
Reverse recovery time	t_{rr}		339.0		ns	$I_S=20\text{ A}$, $di/dt=100\text{ A}/\mu\text{s}$
Reverse recovery charge	Q_{rr}		4.9		μC	
Peak reverse recovery current	I_{rrm}		27.9		A	

■ Note

- 1) Calculated continuous current based on maximum allowable junction temperature.
- 2) Repetitive rating; pulse width limited by max. junction temperature.
- 3) P_d is based on max. junction temperature, using junction-case thermal resistance.
- 4) The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_a=25\text{ }^\circ\text{C}$.
- 5) $V_{DD}=100\text{ V}$, $R_G=50\text{ }\Omega$, $L=10\text{ mH}$, starting $T_j=25\text{ }^\circ\text{C}$.

■ Electrical Characteristics Diagrams



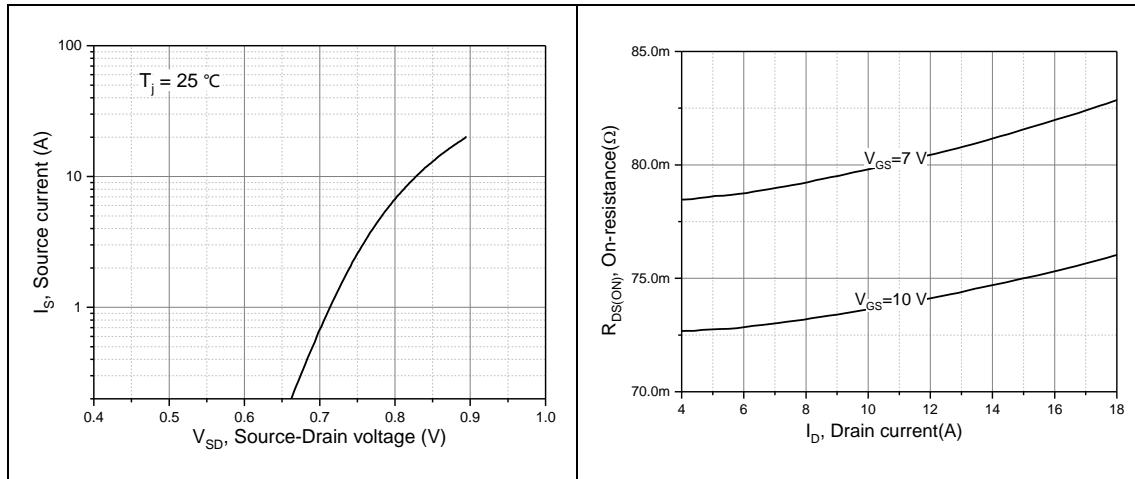


Figure 7, Forward characteristic of body diode

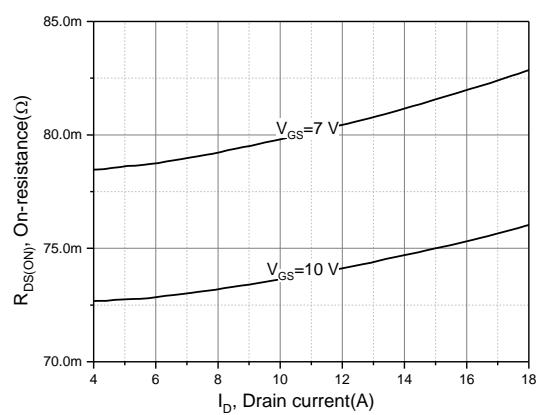


Figure 8, Drain-source on-state resistance

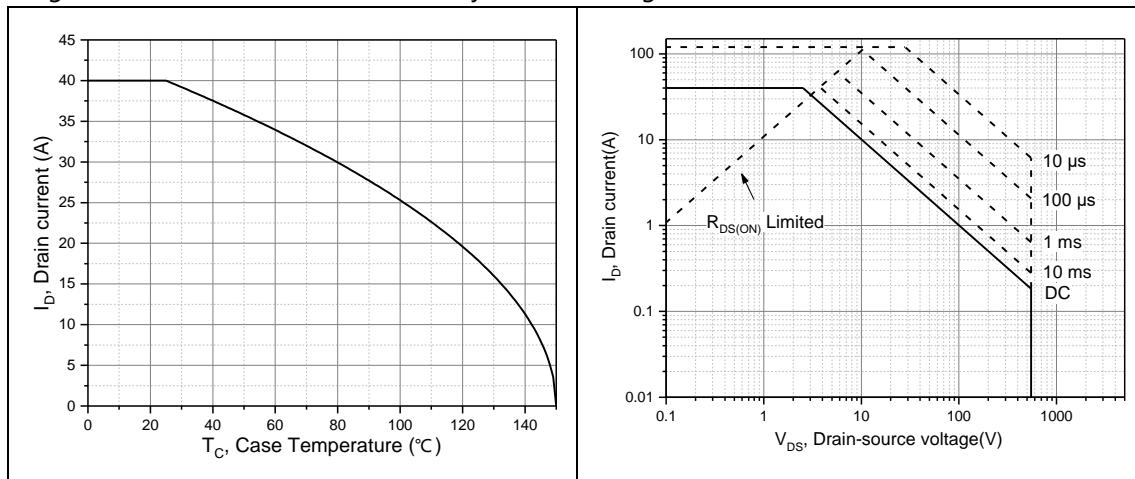
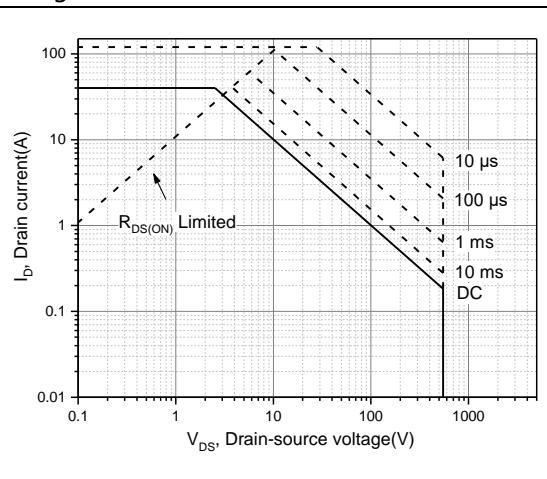


Figure 9, Drain current


 Figure 10, Safe operation area for $T_C=25^\circ\text{C}$

■ Test circuits and waveforms

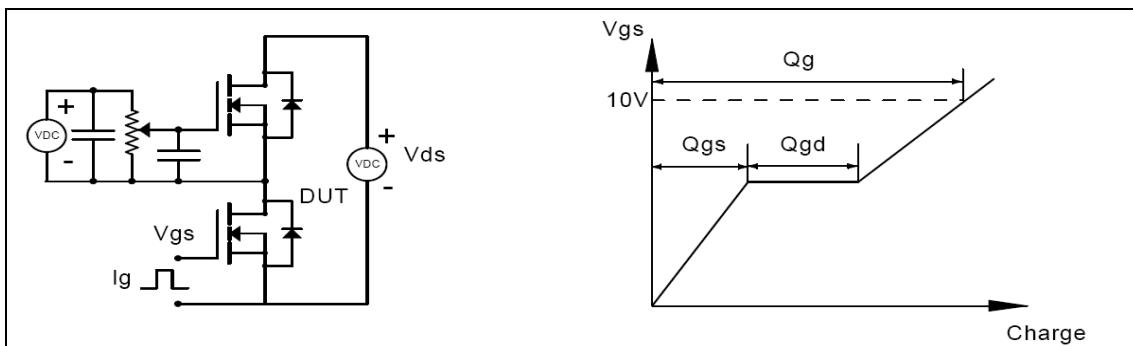


Figure 1, Gate charge test circuit & waveform

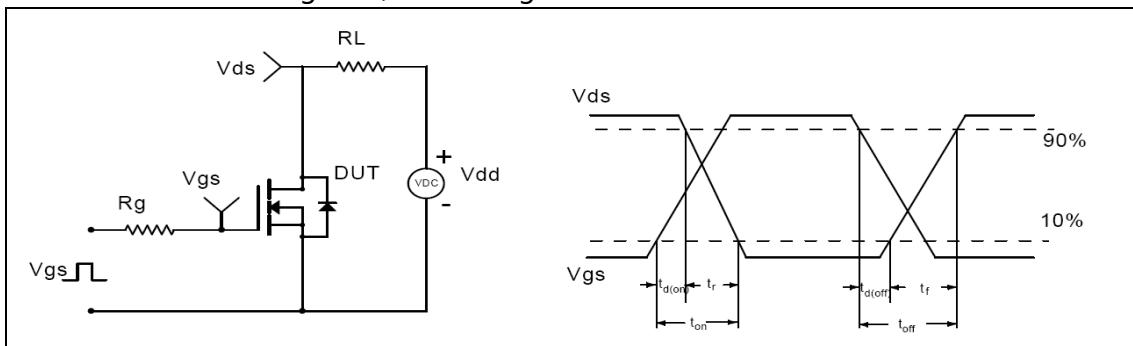


Figure 2, Switching time test circuit & waveforms

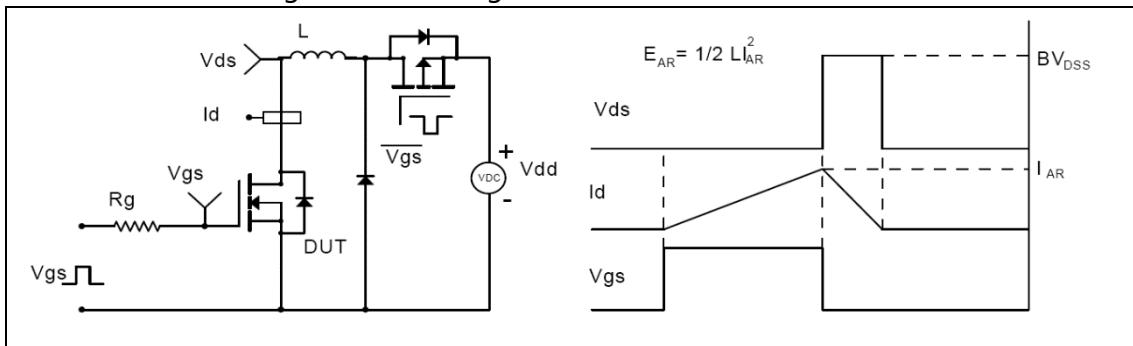


Figure 3, Unclamped inductive switching (UIS) test circuit & waveforms

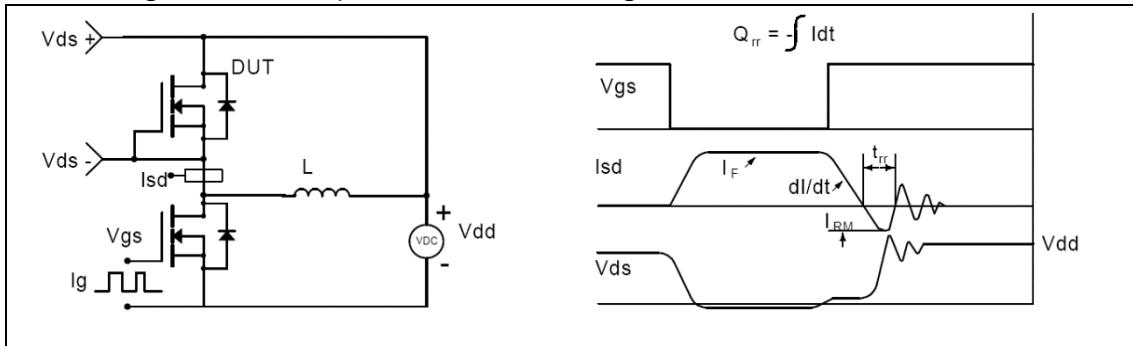
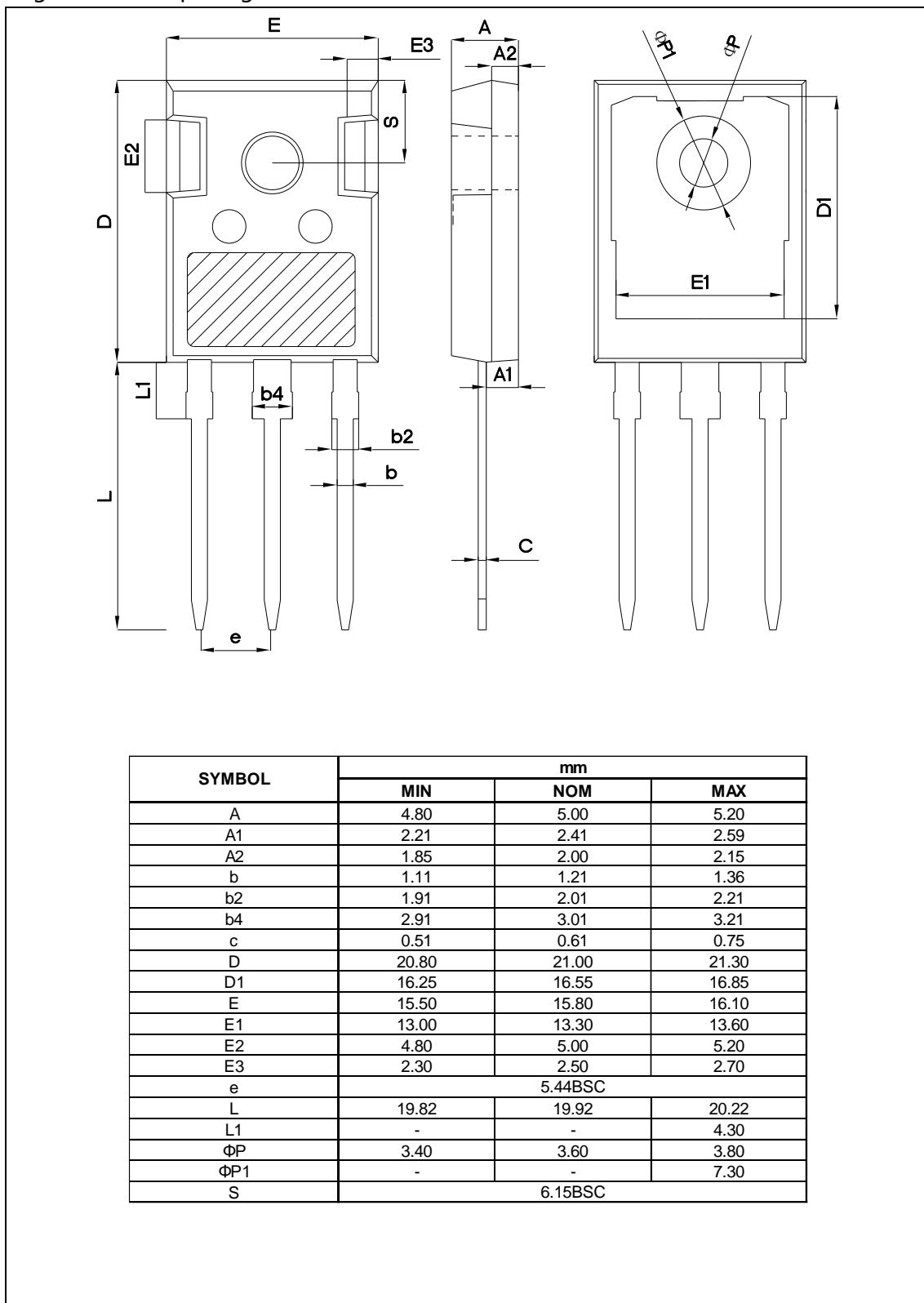


Figure 4, Diode reverse recovery test circuit & waveforms

■ Package Information

Figure1, TO247 package outline dimension



■ Ordering Information

Package	Units/Tube	Tubes/Inner Box	Units/Inner Box	Inner Box/Carton Box	Units/Carton Box
TO247	30	11	330	6	1980

■ Product Information

Product	Package	Pb Free	RoHS	Halogen Free
OSG55R092HF	TO247	yes	yes	yes